

<b>Notice of References Cited</b>	Application/Control No. 09/994,283	Applicant(s)/Patent Under Reexamination CHUN ET AL	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,917,572	06-1999	Kurauchi et al	349/156
	B	US-5,973,763	10-1999	Fujimura et al	349/156
	C	US-5,657,104	08-1997	Kanezawa	349/149
	D	US-6,459,468	10-2000	Shibahara	349/155
	E	US-6,320,639	11-2001	Mori et al	349/155
	F	US-5,982,471	11-1999	Hirakata et al	349/155
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 032 014	08-2000	European	Yamazaki et al	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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